Application/Control No. Applicant(s)/Patent Under Reexamination 10/543,172 KII ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Bai D. Vu 2165 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY * 09-2004 348/231.4 US-2004/0189827 A1 Kim et al. Α * US-2004/0218487 A1 11-2004 369/044.32 В Youn, Jeong Chae US-С US-D US-Ε US-F US-G US-Н US-US-J

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